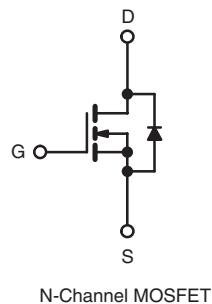
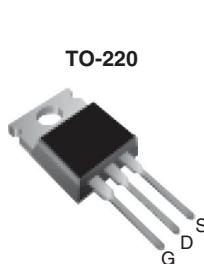


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	60
R _{D(on)} (Ω)	V _{GS} = 5.0 V 0.20
Q _g (Max.) (nC)	8.4
Q _{gs} (nC)	3.5
Q _{gd} (nC)	6.0
Configuration	Single



ORDERING INFORMATION

Package	TO-220
Lead (Pb)-free	IRLZ14PbF SiHLZ14-E3
SnPb	IRLZ14 SiHLZ14

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	60	V
Gate-Source Voltage	V _{GS}	± 10	
Continuous Drain Current	I _D	10 7.2	A
Pulsed Drain Current ^a	I _{DM}	40	
Linear Derating Factor		0.29	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	68	mJ
Maximum Power Dissipation	P _D	43	W
Peak Diode Recovery dV/dt ^c	dV/dt	4.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)		300 ^d	
Mounting Torque		10 1.1	lbf · in N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 793 μH, R_G = 25 Ω, I_{AS} = 10 A (see fig. 12).

c. I_{SD} ≤ 10 A, dI/dt ≤ 90 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



RoHS*
COMPLIANT

FEATURES

- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- R_{D(on)} Specified at V_{GS} = 4 V and 5 V
- 175 °C Operating Temperature
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

THERMAL RESISTANCE

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	-	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	-	3.5	

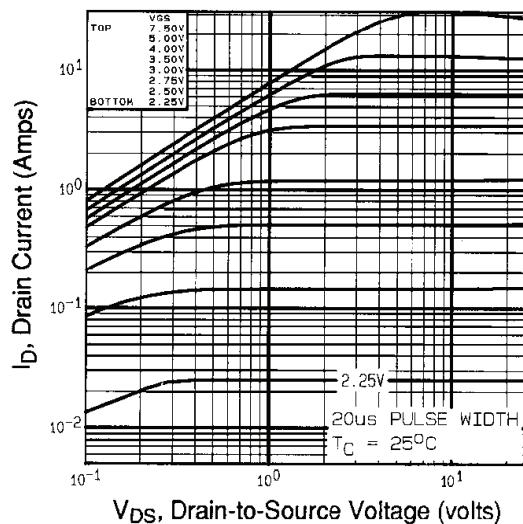
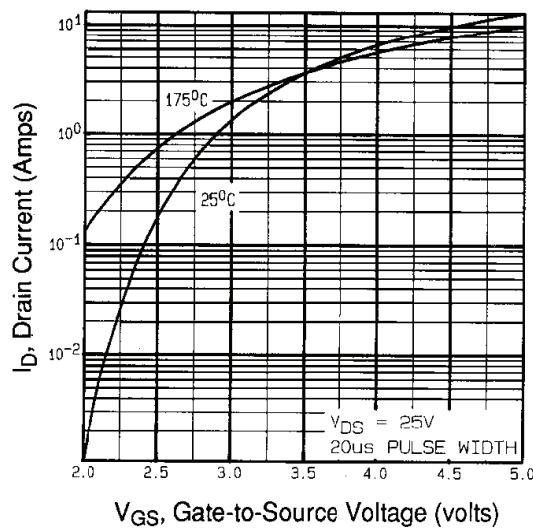
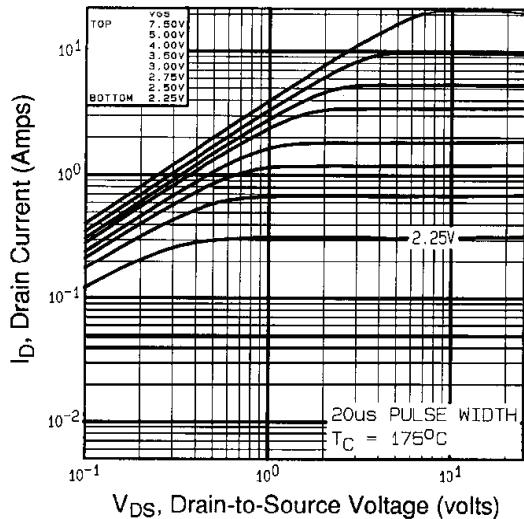
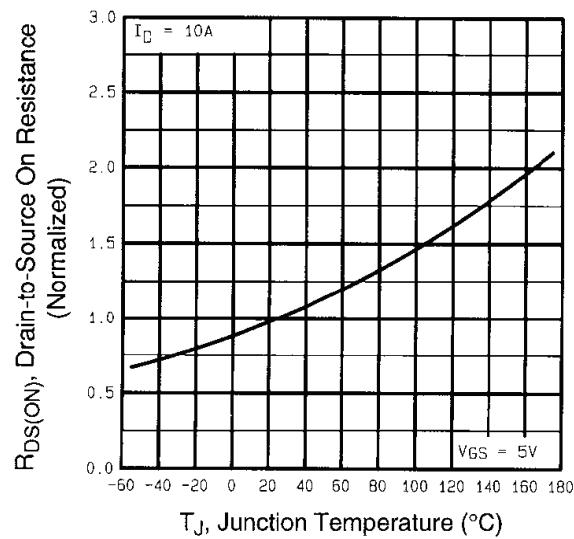
SPECIFICATIONS $T_J = 25^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		60	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.070	-	$^{\circ}\text{C}/\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		1.0	-	2.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 10 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA
		$V_{DS} = 48 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150^{\circ}\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 5.0 \text{ V}$	$I_D = 6.0 \text{ A}^b$	-	-	0.20	Ω
		$V_{GS} = 4.0 \text{ V}$	$I_D = 5.0 \text{ A}^b$	-	-	0.28	
Forward Transconductance	g_{fs}	$V_{DS} = 25 \text{ V}$, $I_D = 6.0 \text{ A}^b$		3.5	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	400	-	pF
Output Capacitance	C_{oss}			-	170	-	
Reverse Transfer Capacitance	C_{rss}			-	42	-	
Total Gate Charge	Q_g	$V_{GS} = 5.0 \text{ V}$	$I_D = 10 \text{ A}$, $V_{DS} = 48 \text{ V}$ see fig. 6 and 13 ^b	-	-	8.4	nC
Gate-Source Charge	Q_{gs}			-	-	3.5	
Gate-Drain Charge	Q_{gd}			-	-	6.0	
Turn-On Delay Time	$t_{d(on)}$			-	9.3	-	
Rise Time	t_r	$V_{DD} = 30 \text{ V}$, $I_D = 10 \text{ A}$ $R_G = 12 \Omega$, $R_D = 2.8 \Omega$ see fig. 10 ^b		-	110	-	ns
Turn-Off Delay Time	$t_{d(off)}$			-	17	-	
Fall Time	t_f			-	26	-	
Internal Drain Inductance	L_D			-	4.5	-	
Internal Source Inductance	L_S	Between lead, 6 mm (0.25") from package and center of die contact		-	7.5	-	nH
Drain-Source Body Diode Characteristics				-	-	-	
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	10	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	40	
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 10 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.6	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = 10 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	93	130	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.34	0.65	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 175^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

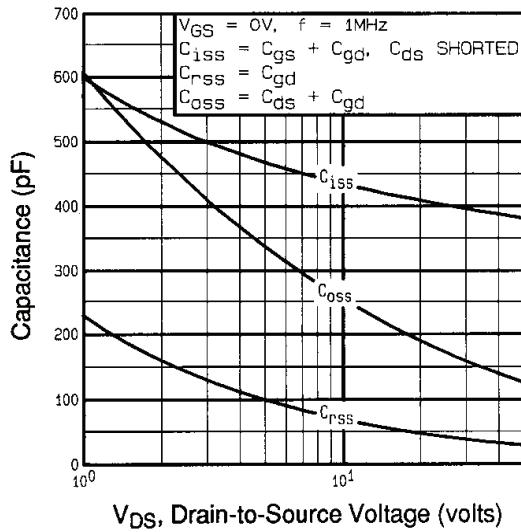


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

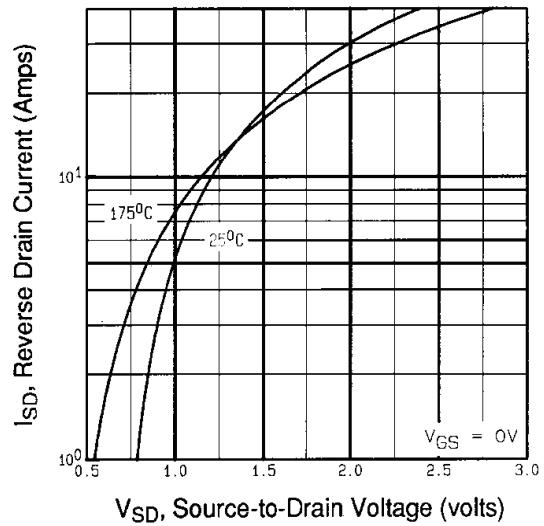


Fig. 7 - Typical Source-Drain Diode Forward Voltage

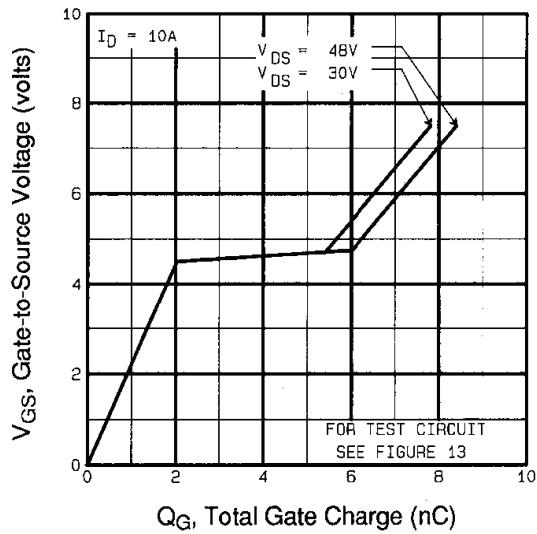


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

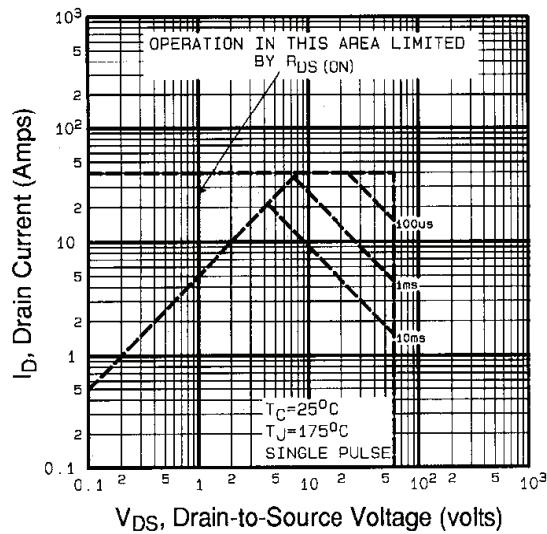


Fig. 8 - Maximum Safe Operating Area

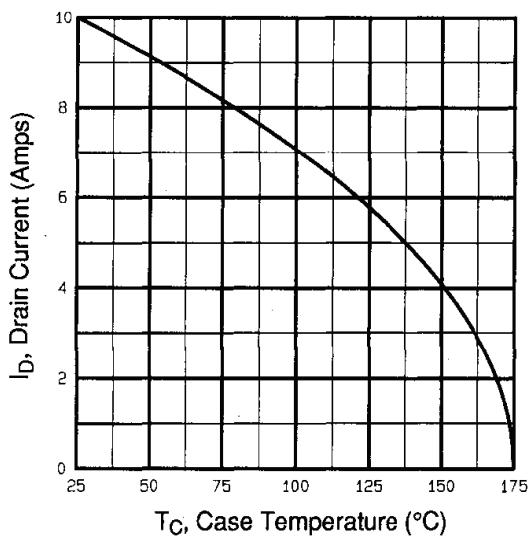


Fig. 9 - Maximum Drain Current vs. Case Temperature

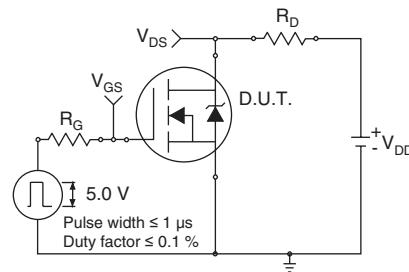


Fig. 10a - Switching Time Test Circuit

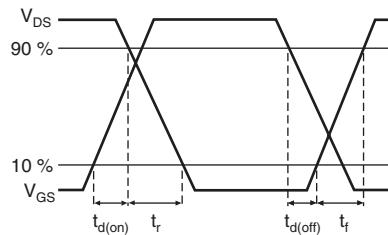


Fig. 10b - Switching Time Waveforms

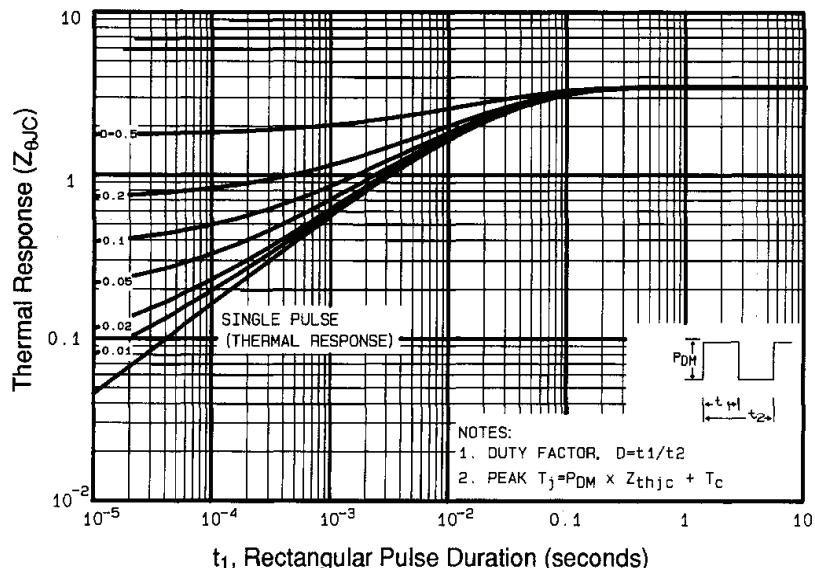


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

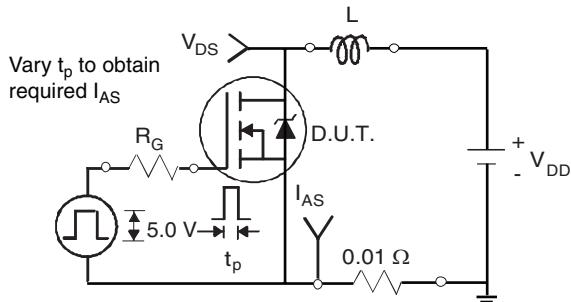


Fig. 12a - Unclamped Inductive Test Circuit

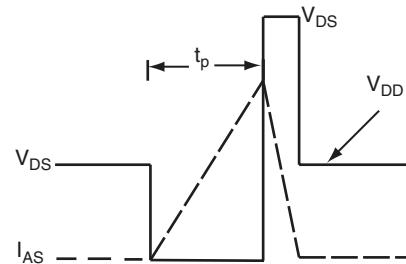


Fig. 12b - Unclamped Inductive Waveforms

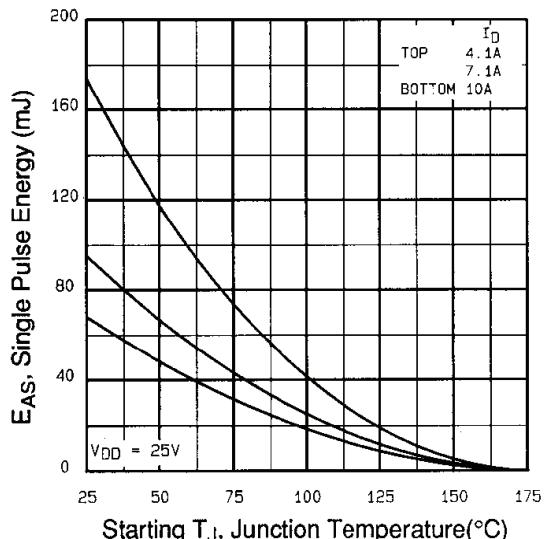


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

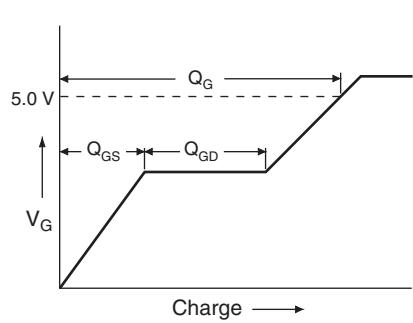


Fig. 13a - Basic Gate Charge Waveform

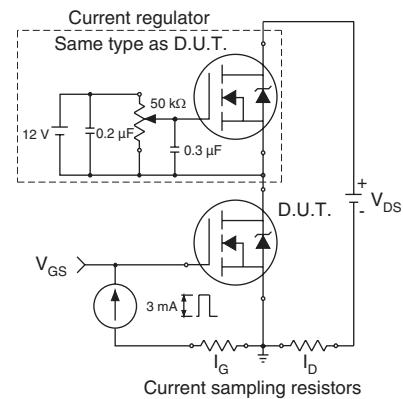
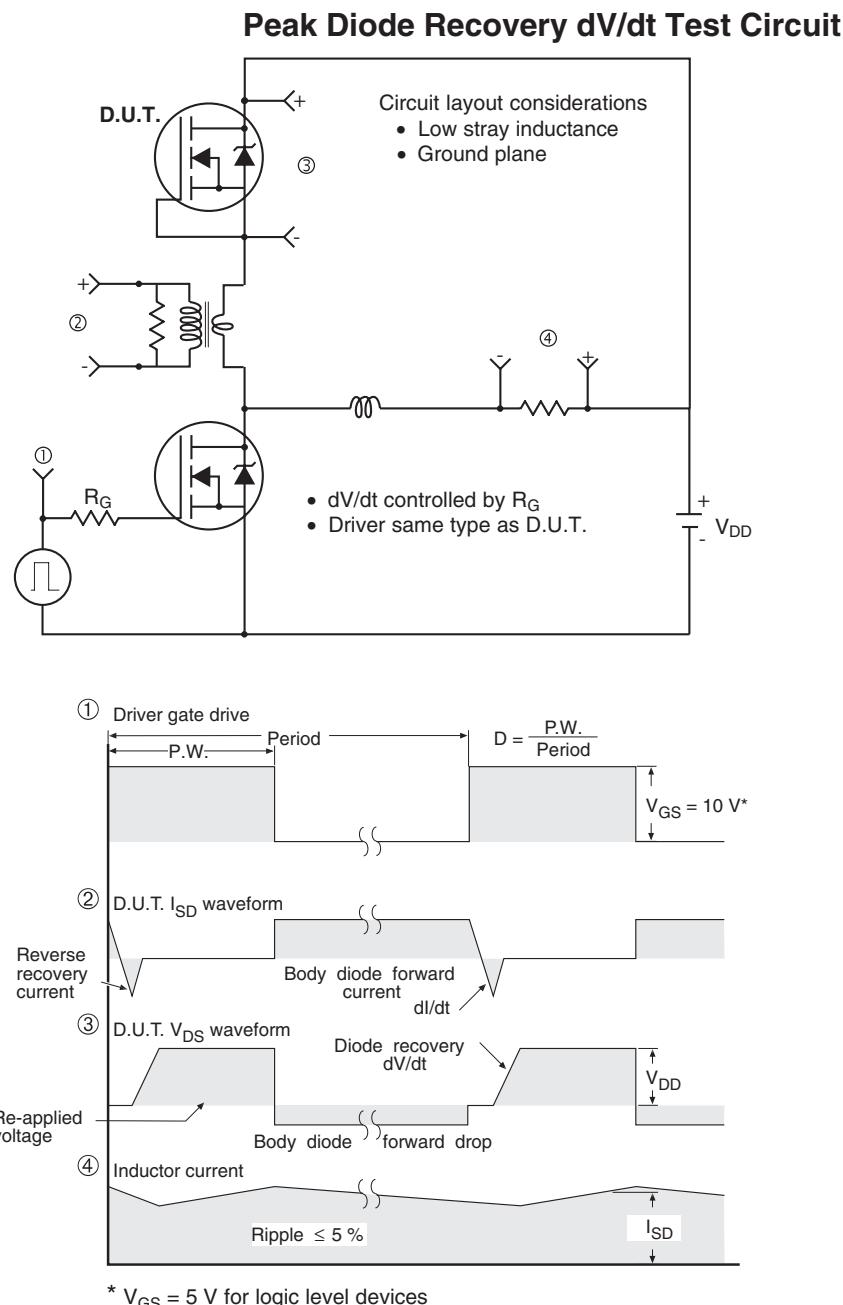


Fig. 13b - Gate Charge Test Circuit


Fig. 14 - For N-Channel

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